



16-BIT, 1.25 MSPS, UNIPOLAR DIFFERENTIAL INPUT, MICRO POWER SAMPLING ANALOG-TO-DIGITAL CONVERTER WITH PARALLEL INTERFACE AND REFERENCE

FEATURES

- 1.25-MHz Sample Rate
- 16-Bit NMC Ensured Over Temperature
- Zero Latency
- Unipolar Differential Input Range: V_{ref} to –V_{ref}
- Onboard Reference
- Onboard Reference Buffer
- High-Speed Parallel Interface
- Power Dissipation: 155 mW at 1.25 MHz Typ
- Wide Digital Supply
- 8-/16-Bit Bus Transfer
- 48-Pin TQFP Package

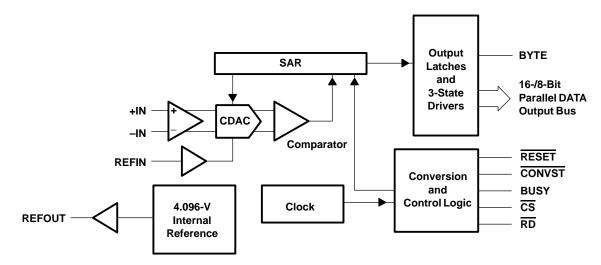
APPLICATIONS

- DWDM
- Instrumentation
- High-Speed, High-Resolution, Zero Latency Data Acquisition Systems
- Transducer Interface
- Medical Instruments
- Communication

DESCRIPTION

The ADS8402 is a 16-bit, 1.25 MHz A/D converter with an internal 4.096-V reference. The device includes a 16-bit capacitor-based SAR A/D converter with inherent sample and hold. The ADS8402 offers a full 16-bit interface and an 8-bit option where data is read using two 8-bit read cycles.

The ADS8402 has a unipolar differential input. It is available in a 48-lead TQFP package and is characterized over the industrial –40°C to 85°C temperature range.





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

ORDERING INFORMATION

MODEL	MAXIMUM INTEGRAL LINEARITY (LSB)	MAXIMUM DIFFERENTIAL LINEARITY (LSB)	NO MISSING CODES RESOLU- TION (BIT)	PACKAGE TYPE	PACKAGE DESIGNATOR	TEMPER- ATURE RANGE	ORDERING INFORMATION	TRANS- PORT MEDIA QUANTITY		
A D 00 4001	10	00	45	48 Pin	050	–40°C to	ADS8402IPFBT	Tape and reel 250		
ADS8402I	±6	-2~+3	15	TQFP	PFB	85	85°C	85°C	ADS8402IPFBR	Tape and reel 1000
A D 00 400 ID	10.5	4 . 0	40	48 Pin	050	–40°C to	ADS8402IBPFBT	Tape and reel 250		
ADS8402IB	±3.5	−1~+2	16	TQFP	PFB	85°C	ADS8402IBPFBR	Tape and reel 1000		

NOTE: For the most current specifications and package information, refer to our website at www.ti.com.

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range unless otherwise noted(1)

				UNIT	
Malta ara	+IN to AGND		+VA + 0.1 V		
Voltage	-IN to AGND			+VA + 0.1 V	
	+VA to AGND			–0.3 V to 7 V	
Voltage range	+VBD to BDGND		–0.3 V to 7 V		
	+VA to +VBD		–0.3 V to 2.5 V		
Digital input voltage to BDGND			-0.3 V to +VBD + 0.3 V		
Digital output voltage to BDGND			-0.3 V to +VBD + 0.3 V		
Operating free-air to	Operating free-air temperature range, T _A			–40°C to 85°C	
Storage temperatu	re range, T _{Stg}			−65°C to 150°C	
Junction temperatu	re (T _J max)			150°C	
	Powerdissipation			(T _J Max – T _A)/θ _{JA}	
TQFP package	θ _{JA} thermal impedance			86°C/W	
		Vapor phase (60 sec)		215°C	
Lead temperature,	soldering	Infrared (15 sec)		220°C	

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



SPECIFICATIONS

 $T_A = -40^{\circ}\text{C}$ to 85°C , +VA = 5 V, +VBD = 3 V or 5 V, V_{ref} = 4.096 V, f_{SAMPLE} = 1.25 MHz (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
Analog Input							
Full-scale input voltage (see Note 1)		+ININ	-V _{ref}		V _{ref}	V	
		+IN	-0.2		V _{ref} + 0.2		
Absolute input voltage Common-mode input range ADS8402		-IN	-0.2		V _{ref} + 0.2	V	
Common-mode input range	ommon-mode input range ADS8402I		$(V_{ref}/2) - 0.2$	V _{ref} /2	$(V_{ref}/2) + 0.2$	V	
Input capacitance	•			25		pF	
Input leakage current				0.5		nA	
System Performance							
Resolution				16		Bits	
	ADS8402I		15				
No missing codes	ADS8402IB		16			Bits	
	ADS8402I		-6	±2.5	6	LSB	
Integral linearity (see Notes 2 and 3)	ADS8402IB		-3.5	±2	3.5		
Differentiallinearity	ADS8402I		-2	±1	3	LSB	
	ADS8402IB		-1	±0.75	2		
Offset error (see Note 4)	ADS8402I		-3	±1	3	mV	
	ADS8402IB		-1.5	±0.5	1.5	mV	
0: () () () ()	ADS8402I		-0.15		0.15	0/.50	
Gain error (see Notes 4 and 5)	ADS8402IB		-0.098		0.098	%FS	
On the second se		At dc (±0.2 V around V _{ref} /2)		80		dB	
Common-mode rejection ratio		$+ININ = 1 V_{pp}$ at 1 MHz		80			
Noise				60		μV RMS	
DC Power supply rejection ratio		At 7FFFh output code, +VA = 4.75 V to 5.25 V, Vref = 4.096 V, See Note 4		1		LSB	
SamplingDynamics							
Conversion time					610	ns	
Acquisition time			150			ns	
Throughputrate					1.25	MHz	
Aperture delay				2		ns	
Aperture jitter				25		ps	
Step response				100		ns	
Overvoltage recovery				100		ns	

⁽¹⁾ Ideal input span, does not include gain or offset error.

⁽²⁾ LSB means least significant bit(3) This is endpoint INL, not best fit

⁽⁴⁾ Measured relative to an ideal full-scale input (+IN - -IN) of 8.192 V

⁽⁵⁾ This specification does not include the internal reference voltage error and drift.



SPECIFICATIONS (CONTINUED)

 $T_A = -40$ °C to 85°C, +VA = +5 V, +VBD = 3 V or 5 V, $V_{ref} = 4.096$ V, $f_{SAMPLE} = 1.25$ MHz (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
DynamicCharacteris	tics	·					
Total harmonic distortion	on (THD) (see Note 1)	$V_{IN} = 8 V_{pp}$ at 100 kHz		-95		dB	
Signal-to-noise ratio (S	iNR)	V _{IN} = 8 V _{pp} at 100 kHz		90		dB	
Signal-to-noise + disto	rtion (SINAD)	V _{IN} = 8 V _{pp} at 100 kHz		88		dB	
Spurious free dynamic	range (SFDR)	V _{IN} = 8 V _{pp} at 100 kHz		95		dB	
-3dB Small signal band	dwidth			5		MHz	
External Voltage Refe	erence Input		•				
Reference voltage at R	REFIN, V _{ref}		2.5	4.096	4.2	V	
Reference resistance ((see Note 2)			500		kΩ	
Internal Reference O	utput	1					
Internal reference start	-up time	From 95% (+VA), with 1 μF storage capacity			120	ms	
V _{ref} range		IOUT = 0	4.065	4.096	4.13	V	
Source Current		Static load			10	μΑ	
Line Regulation		+VA = 4.75 ~ 5.25 V		0.6		mV	
Drift		IOUT = 0		36		PPM/C	
Digital Input/Output		·					
Logicfamily				CMO S			
	VIH	I _{IH} = 5 μA	+VBD-1		+VBD + 0.3		
	VIL	I _I L = 5 μA	-0.3		0.8	V	
Logic level	VOН	I _{OH} = 2 TTL loads	+VBD - 0.6		+VBD		
	VOL	I _{OL} = 2 TTL loads	0		0.4		
Dataformat			Co	2's ompleme	nt		
Power Supply Requir	ements						
D	+VBD (see Notes 3 and 4)		2.95	3.3	5.25	V	
Power supply voltage	+VA (see Note 4)		4.75	5	5.25	V	
+VA Supply current (se	ee Note 5)	f _S = 1.25 MHz		31	34	mA	
Power dissipation (see	Note 5)	f _S = 1.25 MHz		155		mW	
Temperature Range		•	•				
Operatingfree-air			-40		85	°C	
(1) Calculated on the fir	st nine harmonics of the input freque	one.	•				

⁽¹⁾ Calculated on the first nine harmonics of the input frequency
(2) Can vary ±20%
(3) The difference between +VA and +VBD should not be less than 2.3 V, i.e., if +VA is 5.25 V, +VBD should be minimum of 2.95 V.

^{(4) +}VBD ≥ +VA – 2.3 V

⁽⁵⁾ This includes only VA+ current. +VBD current is typically 1 mA with 5 pF load capacitance on output pins.



TIMING CHARACTERISTICS

All specifications typical at -40° C to 85° C, +VA = +VBD = 5 V (see Notes 1, 2, and 3)

PARAMETER	MIN	TYP	MAX	UNIT
Conversion time		600	610	ns
Acquisition time	150			ns
CONVST low to conversion started (BUSY high)			35	ns
Propagation delay time, End of conversion to BUSY low			20	ns
Pulse duration, CONVST low	20			ns
Setup time, CS low to CONVST low	0			ns
Pulse duration, CONVST high	20			ns
CONVST falling edge jitter			10	ps
Pulse duration, BUSY signal low	Min(t _{ACQ})			ns
Pulse duration, BUSY signal high			630	ns
Hold time, First data bus data transition (RD low, or CS low for read cycle, or BYTE input changes) after CONVST low	40			ns
Delay time, CS low to RD low	0			ns
Setup time, RD high to CS high	0			ns
Pulse duration, RD low time	50			ns
Enable time, RD low (or CS low for read cycle) to data valid			20	ns
Delay time, data hold from RD high	0			ns
Delay time, BYTE rising edge or falling edge to data valid	2		20	ns
RD high	20			ns
Hold time, last RD (or CS for read cycle) rising edge to CONVST falling edge	50			ns
Propagation delay time, BUSY falling edge to next RD (or CS for read cycle) falling edge	Max(t _{d5})			ns
Setup time, BYTE rising edge to RD falling edge	0			ns
Hold time, BYTE falling edge to RD falling edge	0			ns
Disable time, RD High (CS high for read cycle) to 3-stated data bus			20	ns
Delay time, BUSY low to MSB data valid			0	ns
	Conversion time Acquisition time CONVST low to conversion started (BUSY high) Propagation delay time, End of conversion to BUSY low Pulse duration, CONVST low Setup time, CS low to CONVST low Pulse duration, CONVST high CONVST falling edge jitter Pulse duration, BUSY signal low Pulse duration, BUSY signal low Pulse duration, BUSY signal high Hold time, First data bus data transition (RD low, or CS low for read cycle, or BYTE input changes) after CONVST low Delay time, CS low to RD low Setup time, RD high to CS high Pulse duration, RD low (or CS low for read cycle) to data valid Delay time, data hold from RD high Delay time, BYTE rising edge or falling edge to data valid RD high Hold time, last RD (or CS for read cycle) rising edge to CONVST falling edge Propagation delay time, BUSY falling edge to next RD (or CS for read cycle) falling edge Betup time, BYTE falling edge to RD falling edge Disable time, RD High (CS high for read cycle) to 3-stated data bus	Acquisition time Acquisition time CONVST low to conversion started (BUSY high) Propagation delay time, End of conversion to BUSY low Pulse duration, CONVST low Setup time, CS low to CONVST low Pulse duration, CONVST high CONVST falling edge jitter Pulse duration, BUSY signal low Pulse duration, BUSY signal high Hold time, First data bus data transition (RD low, or CS low for read cycle, or BYTE input changes) after CONVST low Delay time, CS low to RD low Setup time, RD high to CS high O Setup time, RD low (or CS low for read cycle) to data valid Delay time, Adata hold from RD high Delay time, BYTE rising edge or falling edge to data valid 2 RD high Hold time, last RD (or CS for read cycle) rising edge to CONVST falling edge Fropagation delay time, BUSY falling edge to next RD (or CS for read cycle) falling edge Max(tds) Setup time, BYTE fisling edge to RD falling edge O Disable time, RD High (CS high for read cycle) to 3-stated data bus	Conversion time 150 Acquisition time 150 CONVST low to conversion started (BUSY high) Propagation delay time, End of conversion to BUSY low Pulse duration, CONVST low 20 Setup time, CS low to CONVST low 0 Pulse duration, CONVST high 20 CONVST falling edge jitter Pulse duration, BUSY signal low Min(tACQ) Pulse duration, BUSY signal low Min(tACQ) Pulse duration, BUSY signal high 40 Hold time, First data bus data transition (RD low, or CS low for read cycle, or BYTE input changes) after CONVST low 0 Setup time, CS low to RD low 0 Setup time, RD high to CS high 0 Pulse duration, RD low time 50 Enable time, RD low (or CS low for read cycle) to data valid 0 Delay time, data hold from RD high 0 Delay time, BYTE rising edge or falling edge to data valid 2 RD high 20 Hold time, last RD (or CS for read cycle) rising edge to CONVST falling edge 50 Propagation delay time, BUSY falling edge to RD falling edge 60 Disable time, RD High (CS high for read cycle) to 3-stated data bus	Conversion time 600 610 Acquisition time 150

 ⁽¹⁾ All input signals are specified with t_r = t_f = 5 ns (10% to 90% of +VBD) and timed from a voltage level of (V_{IL} + V_{IH})/2.
 (2) See timing diagrams.
 (3) All timings are measured with 20 pF equivalent loads on all data bits and BUSY pins.



TIMING CHARACTERISTICS

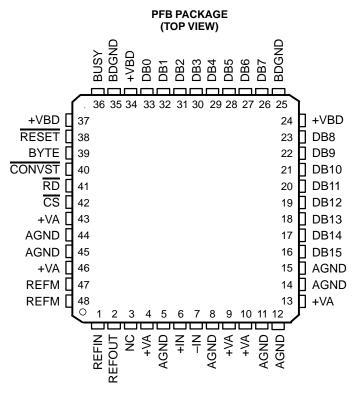
All specifications typical at -40° C to 85° C, +VA = 5 V, +VBD = 3 V (see Notes 1, 2, and 3)

	PARAMETER	MIN	TYP	MAX	UNIT
tCONV	Conversion time		600	610	ns
tACQ	Acquisition time	150			ns
tpd1	CONVST low to conversion started (BUSY high)			40	ns
tpd2	Propagation delay time, end of conversion to BUSY low			20	ns
t _{w1}	Pulse duration, CONVST low	20			ns
tsu1	Setup time, CS low to CONVST low	0			ns
t _{w2}	Pulse duration, CONVST high	20			ns
	CONVST falling edge jitter			10	ps
t _{w3}	Pulse duration, BUSY signal low	Min(t _{ACQ})			ns
t _{w4}	Pulse duration, BUSY signal high			630	ns
t _{h1}	Hold time, first data bus transition (RD low, or CS low for read cycle, or BYTE or BUS 16/16 input changes) after CONVST low	40			ns
^t d1	Delay time, CS low to RD low	0			ns
t _{su2}	Setup time, RD high to CS high	0			ns
t _{w5}	Pulse duration, RD low	50			ns
ten	Enable time, \overline{RD} low (or \overline{CS} low for read cycle) to data valid			30	ns
t _{d2}	Delay time, data hold from RD high	0			ns
t _{d3}	Delay time, BUS16/16 or BYTE rising edge or falling edge to data valid	2		30	ns
t _{w6}	Pulse duration, RD high time	20			ns
t _{h2}	Hold time, last RD (or CS for read cycle) rising edge to CONVST falling edge	50			ns
tpd4	Propagation delay time, BUSY falling edge to next RD (or CS for read cycle) falling edge	Max(td5)			ns
t _{su3}	Setup time, BYTE rising edge to RD falling edge	0			ns
t _{h3}	Hold time, BYTE falling edge to RD falling edge	0			ns
t _{dis}	Disable time, RD High (CS high for read cycle) to 3-stated data bus			30	ns
t _{d5}	Delay time, BUSY low to MSB data valid delay time			0	ns
—					

⁽¹⁾ All input signals are specified with t_r = t_f = 5 ns (10% to 90% of +VBD) and timed from a voltage level of (V_{IL} + V_{IH})/2. (2) See timing diagrams. (3) All timings are measured with 10 pF equivalent loads on all data bits and BUSY pins.



PIN ASSIGNMENTS



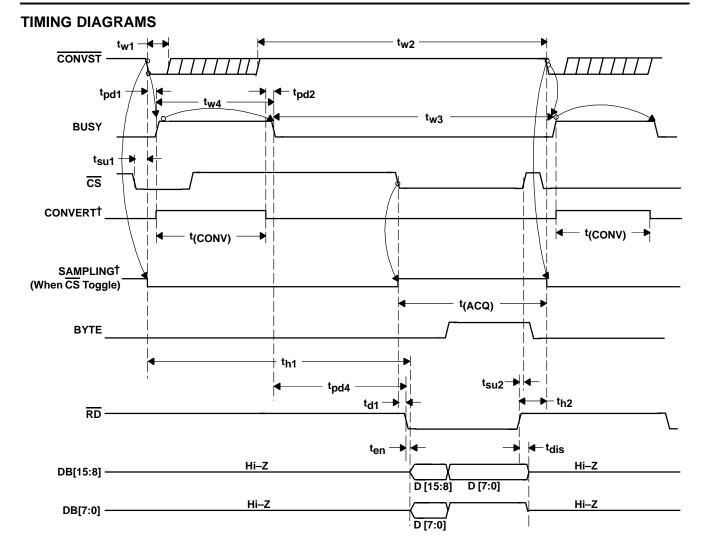
NC - No connection



TERMINAL FUNCTIONS

NAME	NO.	I/O	DESCRIPTION				
AGND	5, 8, 11, 12, 14, 15, 44, 45	_	Analog ground				
BDGND	25, 35	_	Digital ground for bus interface d	gital supply			
BUSY	36	0	Status output. High when a conv	ersion is in progress.			
BYTE	39	I	Byte select input. Used for 8-bit to 0: No fold back 1: Low byte D[7:0] of the 16 mos pins DB[15:8].	ous reading. It significant bits is folded back to h	igh byte of the 16 most significant		
CONVST	40	I	Convert start	nvert start			
CS	42	ı	Chip select				
			8-E	Bit Bus	16-Bit Bus		
Data Bus			BYTE = 0	BYTE = 1	BYTE = 0		
DB15	16	0	D15 (MSB)	D7	D15 (MSB)		
DB14	17	0	D14	D6	D14		
DB13	18	0	D13	D5	D13		
DB12	19	0	D12	D4	D12		
DB11	20	0	D11	D3	D11		
DB10	21	0	D10	D2	D10		
DB9	22	0	D9	D1	D9		
DB8	23	0	D8	D0 (LSB)	D8		
DB7	26	0	D7	Allones	D7		
DB6	27	0	D6	Allones	D6		
DB5	28	0	D5	Allones	D5		
DB4	29	0	D4	Allones	D4		
DB3	30	0	D3	Allones	D3		
DB2	31	0	D2	Allones	D2		
DB1	32	0	D1	Allones	D1		
DB0	33	0	D0 (LSB)	Allones	D0 (LSB)		
-IN	7	ı	Inverting input channel				
+IN	6	ı	Non inverting input channel				
NC	3	_	No connection				
REFIN	1	ı	Reference input				
REFM	47, 48	ı	Reference ground				
REFOUT	2	0	Reference output. Add 1 μF capacitor between the REFOUT pin and REFM pin when internal reference is used.				
RESET	38	I	Current conversion is aborted and output latches are cleared (set to zeros) when this pin is asserted low. RESET works independently of CS.				
RD	41	I	Synchronization pulse for the parallel output.				
+VA	4, 9, 10, 13, 43, 46	-	Analog power supplies, 5-V dc				
+VBD	24, 34, 37	_	Digital power supply for bus				

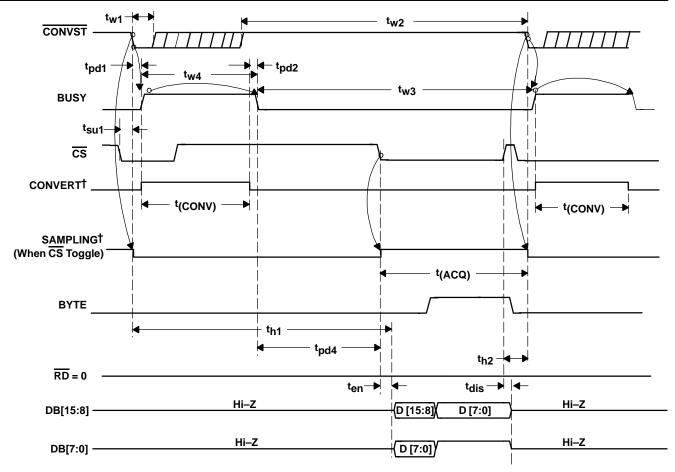




†Signal internal to device

Figure 1. Timing for Conversion and Acquisition Cycles With $\overline{\text{CS}}$ and $\overline{\text{RD}}$ Toggling

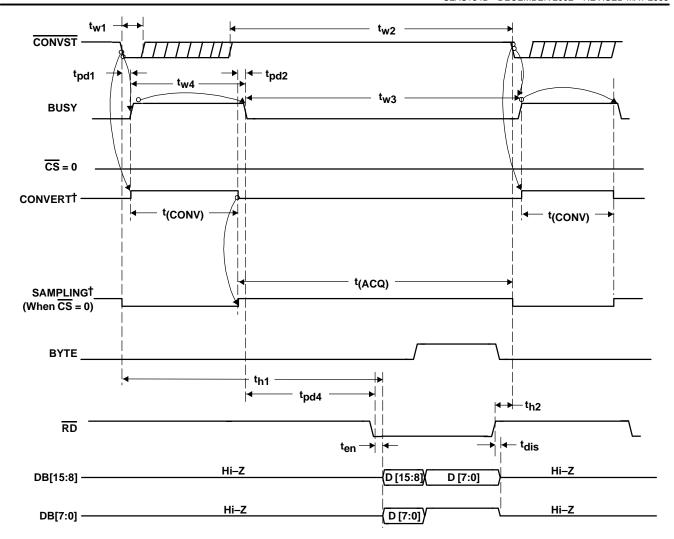




[†]Signal internal to device

Figure 2. Timing for Conversion and Acquisition Cycles With $\overline{\text{CS}}$ Toggling, $\overline{\text{RD}}$ Tied to BDGND

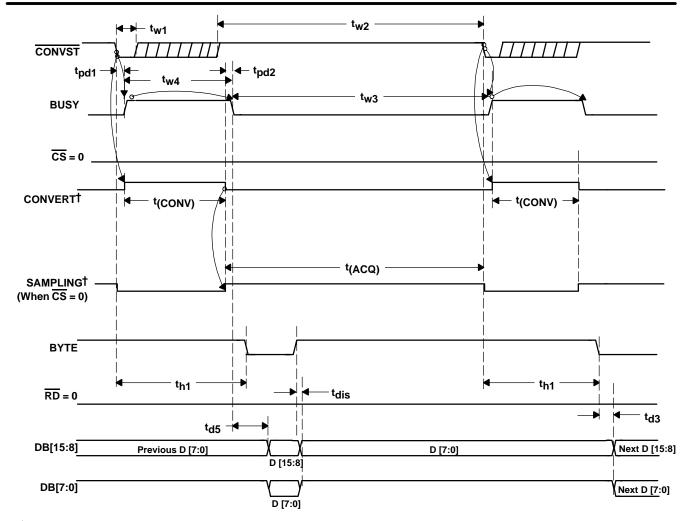




[†]Signal internal to device

Figure 3. Timing for Conversion and Acquisition Cycles With $\overline{\text{CS}}$ Tied to BDGND, $\overline{\text{RD}}$ Toggling





†Signal internal to device

Figure 4. Timing for Conversion and Acquisition Cycles With $\overline{\text{CS}}$ and $\overline{\text{RD}}$ Tied to BDGND—Auto Read

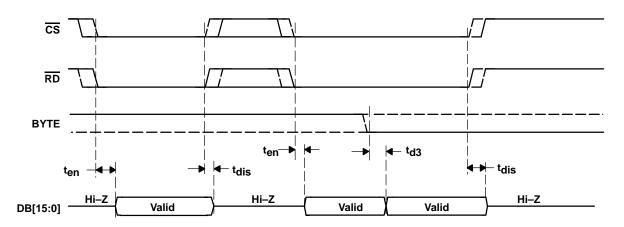
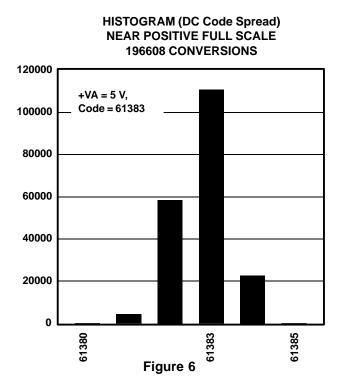
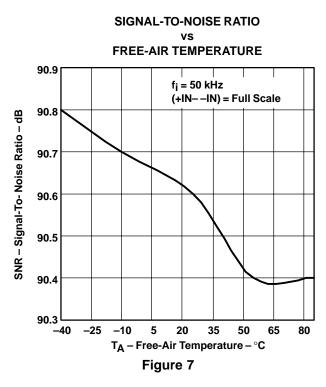


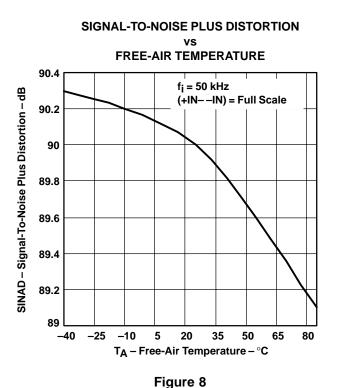
Figure 5. Detailed Timing for Read Cycles

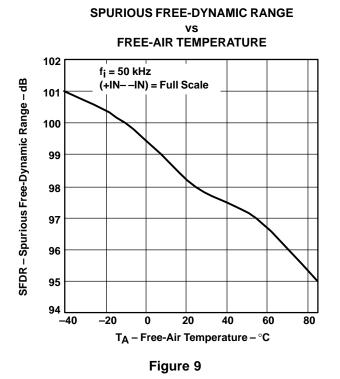


TYPICAL CHARACTERISTICS†



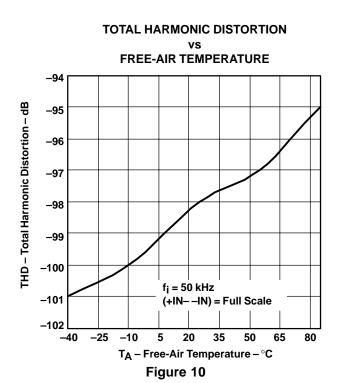


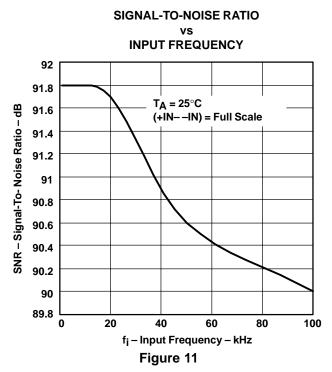


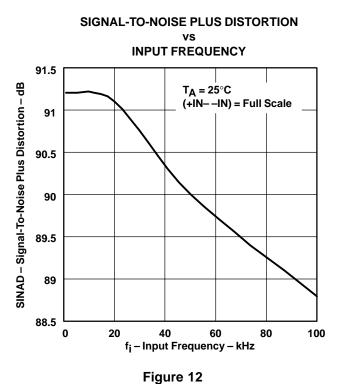


[†] At –40°C to 85°C, +VA = 5 V, +VBD = 5 V, REFIN = 4.096 V (internal reference used) and f_{sample} = 1.25 MHz (unless otherwise noted)









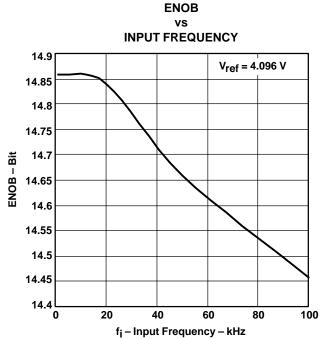


Figure 13

 $^{\ \, ^{\}dagger} \text{At} - 40^{\circ}\text{C to } 85^{\circ}\text{C}, + \text{VA} = 5 \text{ V}, + \text{VBD} = 5 \text{ V}, \\ \text{REFIN} = 4.096 \text{ V (internal reference used)} \\ \text{and } \\ \text{f}_{\text{sample}} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise$

TOTAL HARMONIC DISTORTION



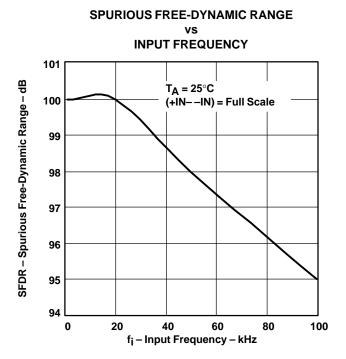
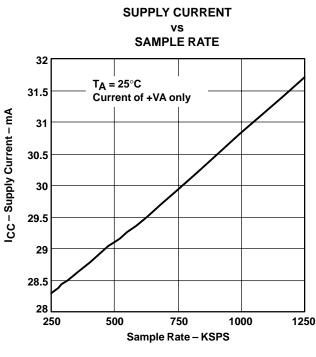


Figure 14

VS INPUT FREQUENCY -94 TA = 25°C (+IN- -IN) = Full Scale -96 -97 -98 -98 -99 -100 -101 0 20 40 60 80 100

Figure 15

f_i - Input Frequency - kHz





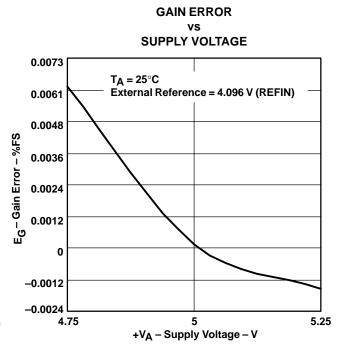
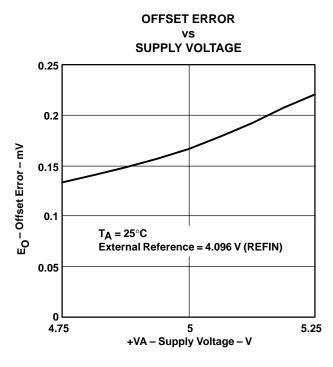


Figure 17

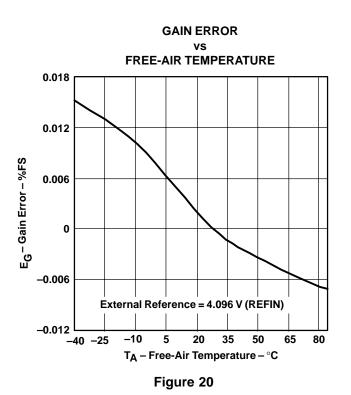




INTERNAL REFERENCE VOLTAGE FREE-AIR TEMPERATURE 4.098 - Internal Reference Voltage - V 4.096 4.094 4.092 Vref 4.090 4.088 -25 5 20 35 50 65 80 -40 -10 T_A – Free-Air Temperature – °C

Figure 18

Figure 19



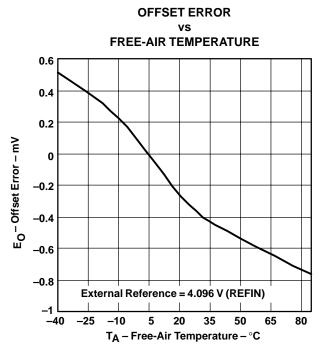


Figure 21

 $[\]dagger$ At -40° C to 85° C, +VA = 5 V, +VBD = 5 V, REFIN = 4.096 V (internal reference used) and $f_{sample} = 1.25$ MHz (unless otherwise noted)



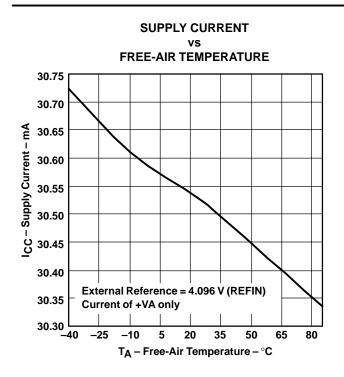


Figure 22

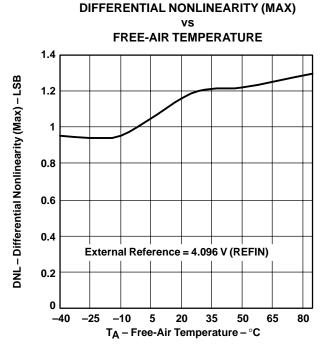


Figure 23

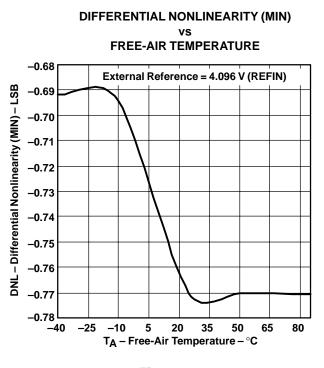


Figure 24

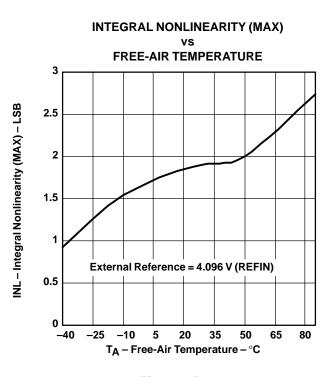
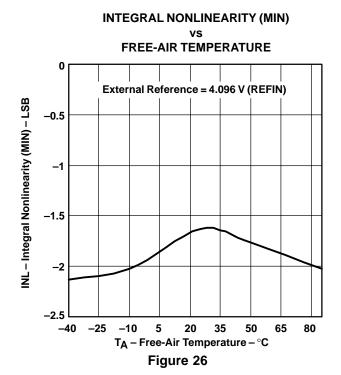
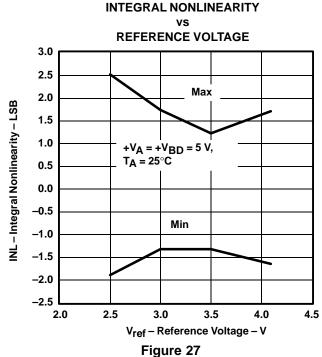


Figure 25

[†] At –40°C to 85°C, +VA = 5 V, +VBD = 5 V, REFIN = 4.096 V (internal reference used) and f_{sample} = 1.25 MHz (unless otherwise noted)







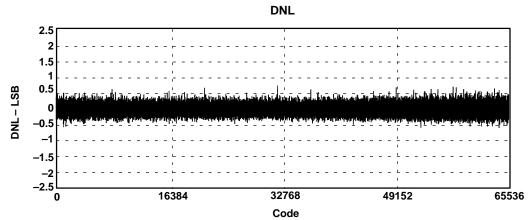
REFERENCE VOLTAGE 3.5 $+V_{A} = +V_{BD} = 5 V,$ 3.0 $T_A = 25^{\circ}C$ DNL - Differential Nonlinearity - LSB 2.5 2.0 Max 1.5 1.0 0.5 0.0 Min -0.5 -1.0 2.5 3.5 4.5 2.0

DIFFERENTIAL NONLINEARITY

V_{ref} – Reference Voltage – V Figure 28

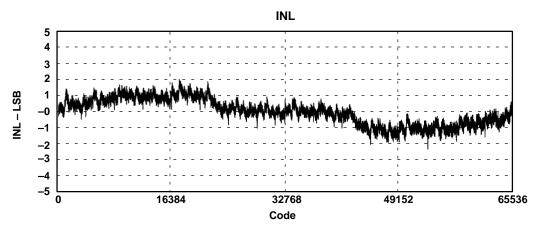
 $^{\ \, ^{\}dagger} \text{At} - 40^{\circ}\text{C to } 85^{\circ}\text{C}, + \text{VA} = 5 \text{ V}, + \text{VBD} = 5 \text{ V}, \\ \text{REFIN} = 4.096 \text{ V (internal reference used)} \\ \text{and } \\ \text{f}_{\text{sample}} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The properties of the results of th$





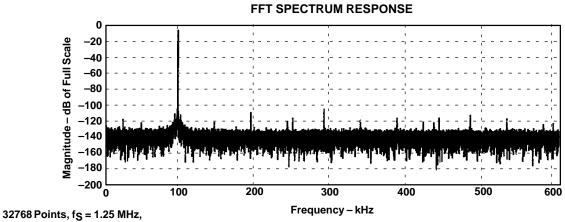
T_A = 25°C, External Reference = 4.096 V (REFIN)

Figure 29



T_A = 25°C, External Reference = 4.096 V (REFIN)

Figure 30



Internal Reference = 4.096 V (REFIN), $T_A = 25^{\circ}C$, $f_i = 100$ kHz, (+IN - -IN) = Full Scale

Figure 31

 $[\]dagger$ At -40° C to 85° C, \pm VA = 5 V, \pm VBD = 5 V, REFIN = 4.096 V (internal reference used) and \dagger sample = 1.25 MHz (unless otherwise noted)



APPLICATION INFORMATION

MICROCONTROLLER INTERFACING

ADS8402 to 8-Bit Microcontroller Interface

Figure 32 shows a parallel interface between the ADS8402 and a typical microcontroller using the 8-bit data bus.

The BUSY signal is used as a falling-edge interrupt to the microcontroller.

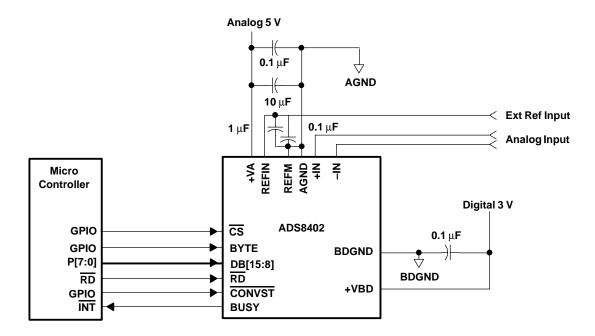


Figure 32. ADS8402 Application Circuitry (using external reference)

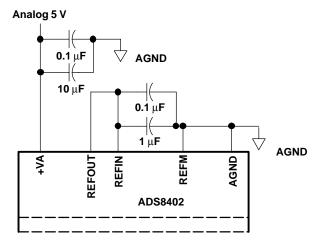


Figure 33. Use Internal Reference



PRINCIPLES OF OPERATION

The ADS8402 is a high-speed successive approximation register (SAR) analog-to-digital converter (ADC). The architecture is based on charge redistribution, which inherently includes a sample/hold function. See Figure 32 for the application circuit for the ADS8402.

The conversion clock is generated internally. The conversion time of 610 ns is capable of sustaining a 1.25-MHz throughput.

The analog input is provided to two input pins: +IN and -IN. When a conversion is initiated, the differential input on these pins is sampled on the internal capacitor array. While a conversion is in progress, both inputs are disconnected from any internal function.

REFERENCE

The ADS8402 can operate with an external reference with a range from 2.5 V to 4.2 V. A 4.096-V internal reference is included. When internal reference is used, pin 2 (REFOUT) should be connected to pin 1 (REFIN) with an 0.1 μ F decoupling capacitor and 1 μ F storage capacitor between pin 2 (REFOUT) and pins 47 and 48 (REFM) (see Figure 33). The internal reference of the converter is double buffered. If an external reference is used, the second buffer provides isolation between the external reference and the CDAC. This buffer is also used to recharge all of the capacitors of the CDAC during conversion. Pin 2 (REFOUT) can be left unconnected (floating) if external reference is used.

ANALOG INPUT

When the converter enters the hold mode, the voltage difference between the +IN and –IN inputs is captured on the internal capacitor array. Both +IN and –IN input has a range of –0.2 V to V_{ref} + 0.2 V. The input span (+IN – (–IN)) is limited to $-V_{ref}$ to V_{ref} .

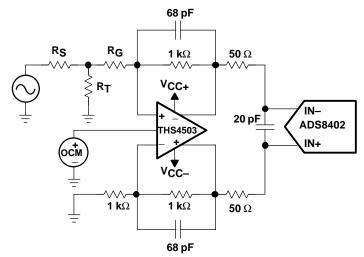
The input current on the analog inputs depends upon a number of factors: sample rate, input voltage, and source impedance. Essentially, the current into the ADS8402 charges the internal capacitor array during the sample period. After this capacitance has been fully charged, there is no further input current. The source of the analog input voltage must be able to charge the input capacitance (25 pF) to an 16-bit settling level within the acquisition time (150 ns) of the device. When the converter goes into the hold mode, the input impedance is greater than 1 $G\Omega$.

Care must be taken regarding the absolute analog input voltage. To maintain the linearity of the converter, the \pm IN and \pm IN inputs and the span (\pm IN – (\pm IN)) should be within the limits specified. Outside of these ranges, the converter's linearity may not meet specifications. To minimize noise, low bandwidth input signals with low-pass filters should be used.

Care should be taken to ensure that the output impedance of the sources driving +IN and -IN inputs are matched. If this is not observed, the two inputs could have different setting time. This may result in offset error, gain error and linearity error which varies with temperature and input voltage.

A typical input circuit using Tl's THS4503 is shown in Figure 34. Input from a single-ended source may be converted into differential signal for ADS8402 as shown in the figure. In case the source itself is differential then THS4503 may be used in differential input and differential output mode.





R_G, R_S, and R_T should be chosen such that R_G + R_S \parallel R_T = 1 k Ω V_{OCM} = 2 V, +V_{CC} = 7 V, and -V_{CC} = -7 V

Figure 34. Using THS4503 With ADS8402

DIGITAL INTERFACE

Timing and Control

See the timing diagrams in the specifications section for detailed information on timing signals and their requirements.

The ADS8402 uses an internal oscillator generated clock which controls the conversion rate and in turn the throughput of the converter. No external clock input is required.

Conversions are initiated by bringing the $\overline{\text{CONVST}}$ pin low for a minimum of 20 ns (after the 20 ns minimum requirement has been met, the $\overline{\text{CONVST}}$ pin can be brought high), while $\overline{\text{CS}}$ is low. The ADS8402 switches from the sample to the hold mode on the falling edge of the $\overline{\text{CONVST}}$ command. A clean and low jitter falling edge of this signal is important to the performance of the converter. The BUSY output is brought high after $\overline{\text{CONVST}}$ goes low. BUSY stays high throughout the conversion process and returns low when the conversion has ended.

Sampling starts with the falling edge of the BUSY signal when \overline{CS} is tied low or starts with the falling edge of \overline{CS} when BUSY is low.

Both \overline{RD} and \overline{CS} can be high during and before a conversion with one exception (\overline{CS} must be low when \overline{CONVST} goes low to initiate a conversion). Both the \overline{RD} and \overline{CS} pins are brought low in order to enable the parallel output bus with the conversion.

Reading Data

The ADS8402 outputs full parallel data in two's complement format as shown in Table 1. The parallel output is active when $\overline{\text{CS}}$ and $\overline{\text{RD}}$ are both low. There is a minimal quiet zone requirement around the falling edge of $\overline{\text{CONVST}}$. This is 100 ns prior to the falling edge of $\overline{\text{CONVST}}$ and 40 ns after the falling edge. No data read should be attempted within this zone. Any other combination of $\overline{\text{CS}}$ and $\overline{\text{RD}}$ sets the parallel output to 3-state. BYTE is used for multiword read operations. BYTE is used whenever lower bits of the conversion result are output on the higher byte of the bus. Refer to Table 1 for ideal output codes.



Table 1.	Ideal Input	Voltages	and O	utput C	Codes

DESCRIPTION	ANALOG VALUE	DIGITAL GUITDUT TWOC	OMBI EMENT
FULL SCALE RANGE	2V _{ref}	DIGITAL OUTPUT TWOS C	OMPLEMENT
Least significant bit (LSB)	2V _{ref} /65536	BINARY CODE	HEX CODE
Full scale	V _{ref}	0111 1111 1111 1111	7FFF
Midscale	0	0000 0000 0000 0000	0000
Zero	-V _{ref}	1000 0000 0000 0000	8000

The output data is a full 16-bit word (D15-D0) on DB15-DB0 pins (MSB-LSB) if BYTE is low.

The result may also be read on an 8-bit bus for convenience. This is done by using only pins DB15–DB8. In this case two reads are necessary: the first as before, leaving BYTE low and reading the 8 most significant bits on pins DB15–DB8, then bringing BYTE high. When BYTE is high, the low bits (D7–D0) appears on pins DB15–D8.

These multiword read operations can be done with multiple active RD (toggling) or with RD tied low for simplicity.

DVTE	DATA READ OUT			
BYTE	DB15-DB8	DB7-DB0		
High	D7-D0	All one's		
Low	D15-D8	D7-D0		

RESET

 $\overline{\text{RESET}}$ is an asynchronous active low input signal (that works independently of $\overline{\text{CS}}$). Minimum $\overline{\text{RESET}}$ low time is 20 ns. Current conversion will be aborted no later than 50 ns after the converter is in the reset mode. In addition, all output latches are cleared (set to zero's) after $\overline{\text{RESET}}$. The converter goes back to normal operation mode no later than 20 ns after $\overline{\text{RESET}}$ input is brought high.

The converter starts the first sampling period 20 ns after the rising edge of RESET. Any sampling period except for the one immediately after a RESET is started with the falling edge of the previous BUSY signal or the falling edge of CS, whichever is later.

POWER-ON INITIALIZATION

One RESET pulse followed by three conversion cycles must be given to the converter after powerup to ensure proper operation. The next pulse can be issued once both +VA and +VBD reach 95% of the minimum required value.

LAYOUT

For optimum performance, care should be taken with the physical layout of the ADS8402 circuitry.

As the ADS8402 offers single-supply operation, it is often used in close proximity with digital logic, microcontrollers, microprocessors, and digital signal processors. The more digital logic present in the design and the higher the switching speed, the more difficult it is to achieve good performance from the converter.

The basic SAR architecture is sensitive to glitches or sudden changes on the power supply, reference, ground connections and digital inputs that occur just prior to latching the output of the analog comparator. Thus, driving any single conversion for an n-bit SAR converter, there are at least n *windows* in which large external transient voltages can affect the conversion result. Such glitches might originate from switching power supplies, nearby digital logic, or high power devices.

The degree of error in the digital output depends on the reference voltage, layout, and the exact timing of the external event.

On average, the ADS8402 draws very little current from an external reference, as the reference voltage is internally buffered. If the reference voltage is external and originates from an op amp, make sure that it can drive the bypass capacitor or capacitors without oscillation. A 0.1- μ F bypass capacitor and 1- μ F storage capacitor are recommended from pin 1 (REFIN) directly to pin 48 (REFM). REFM and AGND should be shorted on the same ground plane under the device.

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The AGND and BDGND pins should be connected to a clean ground point. In all cases, this should be the analog ground. Avoid connections which are close to the grounding point of a microcontroller or digital signal processor. If required, run a ground trace directly from the converter to the power supply entry point. The ideal layout consists of an analog ground plane dedicated to the converter and associated analog circuitry.

As with the AGND connections, +VA should be connected to a 5-V power supply plane or trace that is separate from the connection for digital logic until they are connected at the power entry point. Power to the ADS8402 should be clean and well bypassed. A 0.1- μ F ceramic bypass capacitor should be placed as close to the device as possible. See Table 2 for the placement of the capacitor. In addition, a 1- μ F to 10- μ F capacitor is recommended. In some situations, additional bypassing may be required, such as a 100- μ F electrolytic capacitor or even a Pi filter made up of inductors and capacitors—all designed to essentially low-pass filter the 5-V supply, removing the high frequency noise.

Table 2. Power Supply Decoupling Capacitor Placement

POWER SUPPLY PLANE	CONVERTED ANALOG SIDE	CONVERTED DIGITAL SIDE	
SUPPLY PINS	CONVERTER ANALOG SIDE	CONVERTER DIGITAL SIDE	
Pin pairs that require shortest path to decoupling capacitors	(4,5), (8,9), (10,11), (13,15), (43,44), (45,46)	(24,25), (34, 35)	
Pins that require no decoupling	12, 14	37	

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